

# **x-correlation in wavelet domain for detection of stochastic gravitational waves**

S.Klimenko, University of Florida

## **Outline**

- **Introduction**
- **Optimal cross-correlation**
- **Correlation tests**
- **Cross-correlation in wavelet domain**
- **Correlated noise**
- **Conclusion**

- **Stochastic Gravitational Waves**
  - from early universe or/and large number of unresolved sources

(GW energy density)/(closure density)

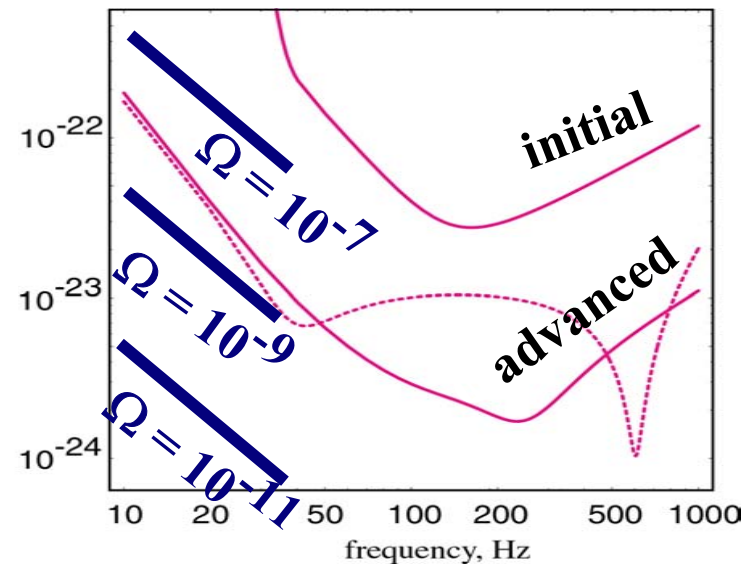
$$\Omega_{GW} < 10^{-5}$$

- **Detection of SGW**

- x-correlation of detectors output  $s_L(t)$  and  $s_H(t)$

$$S = \int_0^T dt \int_0^T dt' s_L(t') s_H(t) Q(t-t', \Omega_L, \Omega_H)$$

- $Q$  - optimal kernel,  $T$  – observation time
- $\Omega_H$  ( $\Omega_L$ ) is the orientation of H (L) interferometer



- **x-correlation in Fourier domain** (B.Allen,J.Romano gr- qc/ 9604033 v3 30

Sep 96)

$$S = \int_{-\infty}^{\infty} df \tilde{s}_H(f) \tilde{s}_L^*(f) Q(f, \Omega_L, \Omega_H)$$

- **Optimal kernel:**

$$Q(f, \Omega_L, \Omega_H) = \frac{|f|^{-3} \Omega_{GW}(f) \gamma(f, \Omega_L, \Omega_H)}{P_L(f) P_H(f)}$$

- ✓  $\Omega_{GW}$  – SGW strength

- ✓  $P_L, P_H$  - spectral densities of detector noise

- ✓  $\gamma$  – detector overlap function (E. Flanagan, Phys. Rev. D48, 2389 (1993))

- **Questions:**

- What is *distribution of S* if noise is not Gaussian?
- What to do if noise is not stationary?
- What to do if *S* is affected by correlated (©) noise?

- **linear correlation test**

$$r = \frac{\sum_i (x_i - \bar{x})(y_i - \bar{y})}{\sqrt{\sum (x_i - \bar{x})^2} \sqrt{\sum (y_i - \bar{y})^2}}$$

- correlation coefficient

- parametric: no universal way to compute  $r$  distribution
- if data is not Gaussian,  $r$  is a poor statistics to decide
  - ✓ correlation is statistically significant
  - ✓ one observed correlation is stronger than another.

- **rank correlation test**

- non-parametric: exactly known  $r$  distribution
- effective but CPU inefficient for large data sets

- Sign transform:  $u_i = \text{sign}(x_i - \hat{x})$ 
  - $\hat{x}$  - median of  $x$
- Sign statistics:  $s_i = \text{sign}(x_i - \hat{x}) \cdot \text{sign}(y_i - \hat{y})$
- Correlation coefficient  $\gamma$ :  $\gamma = \text{mean}(s_i)$
- Distribution of  $\gamma$  ( $n$  - number of samples):
  - Gaussian (large  $n$ ):  $P(n, \gamma) \approx \sqrt{\frac{n}{2\pi}} \cdot \exp\left(-\frac{n\gamma^2}{2}\right)$
- very robust:
  - error from  $\hat{x}$  and  $\hat{y} \sim 2/n^2$ , much less than  $\text{var}(\gamma) = 1/n$  for large  $n$

- **Data:** simulated uncorrelated noise (n) + Gaussian signal (g)

$$x = n_x + g, \quad y = n_y + g$$

- **Test efficiency:**  $\varepsilon_s = r_s / r_L$

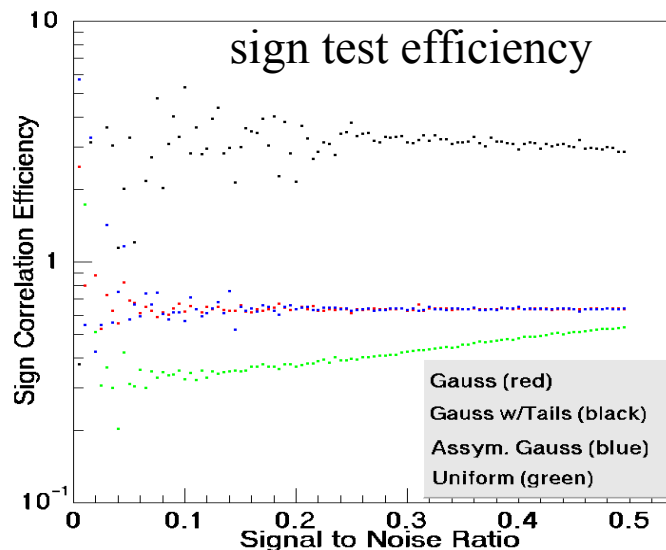
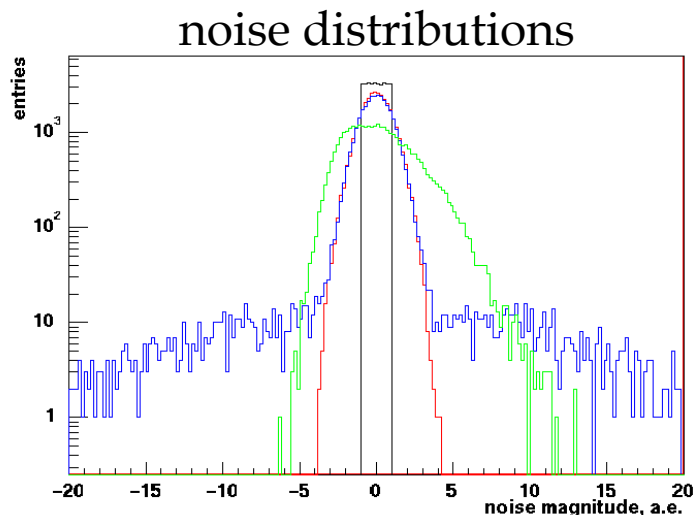
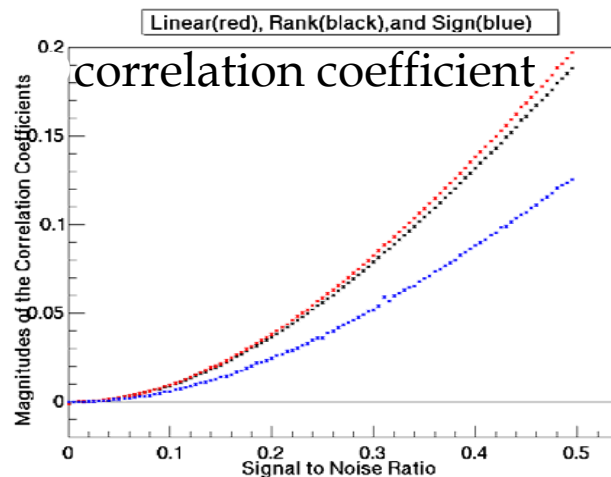
➤ for Gaussian noise

✓ rank test efficiency - 95%

✓ sign test efficiency - 64%

**(2.5 times more data)**

➤ independent on SNR



- time-frequency representation of data in wavelet domain

➤  $P_{mn}$  :  $n$  – scale (frequency) index,  $m$  – time index

- due to of locality of wavelet basis, wavelet layers are decimated time series (similar to windowed FT).

- X-correlation

$$S = \sum_{nm} \sum_{k,l} p_{kl} q_{mn} I_{kl,mn}$$

$$I_{kl,mn} = \int_0^T dt \int_0^T dt' \psi_{kl}(t') \psi_{mn}(t) Q(t-t', \Omega_L, \Omega_H)$$

➤  $\Psi_{nm}$  – basis of wavelet functions

- **x-correlation is a sum over wavelet layers**

$$S = \sum_{n,\tau} w_n(\tau) r_n(\tau)$$

$$w_n(\tau) = N_n \int_{-\infty}^{\infty} df |\psi_n(f)|^2 \frac{\Omega_{GW}(f) \gamma(f, \Omega_L, \Omega_H)}{|f|^3} \frac{\sigma_{nL}}{P_L(f)} \cdot \frac{\sigma_{nH}}{P_H(f)} \exp(-j2\pi f \tau)$$

- $\tau$  – time lag
- $n$  – wavelet layer number
- $N_n$  – number of samples in layer  $n$
- $r_n(\tau)$  – correlation coefficients as a function of lag time  $\tau$
- $w_n(\tau)$  – optimal weight
  - ✓  $\Psi_n$  – Fourier image of mother wavelet for layer  $n$
  - ✓  $\sigma_{nL}, \sigma_{nH}$  – noise *rms* in wavelet domain for detector L (H)
- **equivalent to  $S$  calculated in Time & Fourier domains**



- replace  $r_n(\tau)$  with  $\gamma_n(\tau)$  - sign correlation coefficients
- To keep the weights optimal, take into account the sign correlation efficiency  $\varepsilon_n$

$$S_s = \sum_{n,\tau} \tilde{w}_n(\tau) \gamma_n(\tau), \quad \tilde{w}_n(\tau) = w_n(\tau) \varepsilon_n$$

- $\gamma_n(\tau)$  are normally distributed with variance  $1/N_n$

➤ then the x-correlation variance is:

$$\text{var}(S_s) = \sum_{n,\tau} \frac{1}{N_n} \tilde{w}_n^2(\tau)$$

- What we gain/lose

➤ sign test is less efficient (65%) when data is Gaussian:

➤ if data is not Gaussian

✓ the sign test can be more efficient

✓ gain confidence in calculation of S distribution

- **Optimal weight**

$$\tilde{w}_n(\tau) = N_n \int_{-\infty}^{\infty} df |\psi_n(f)|^2 |f|^{-3} \frac{\Omega_{GW}(f) \cdot \gamma(f, \Omega_L, \Omega_H)}{A_L(f) \cdot A_H(f)} \exp(-j2\pi f\tau)$$

- **“noise amplitude”**

$$A_I(f) = \frac{P_I(f)}{\sigma_{nI} \sqrt{\epsilon_n}}$$

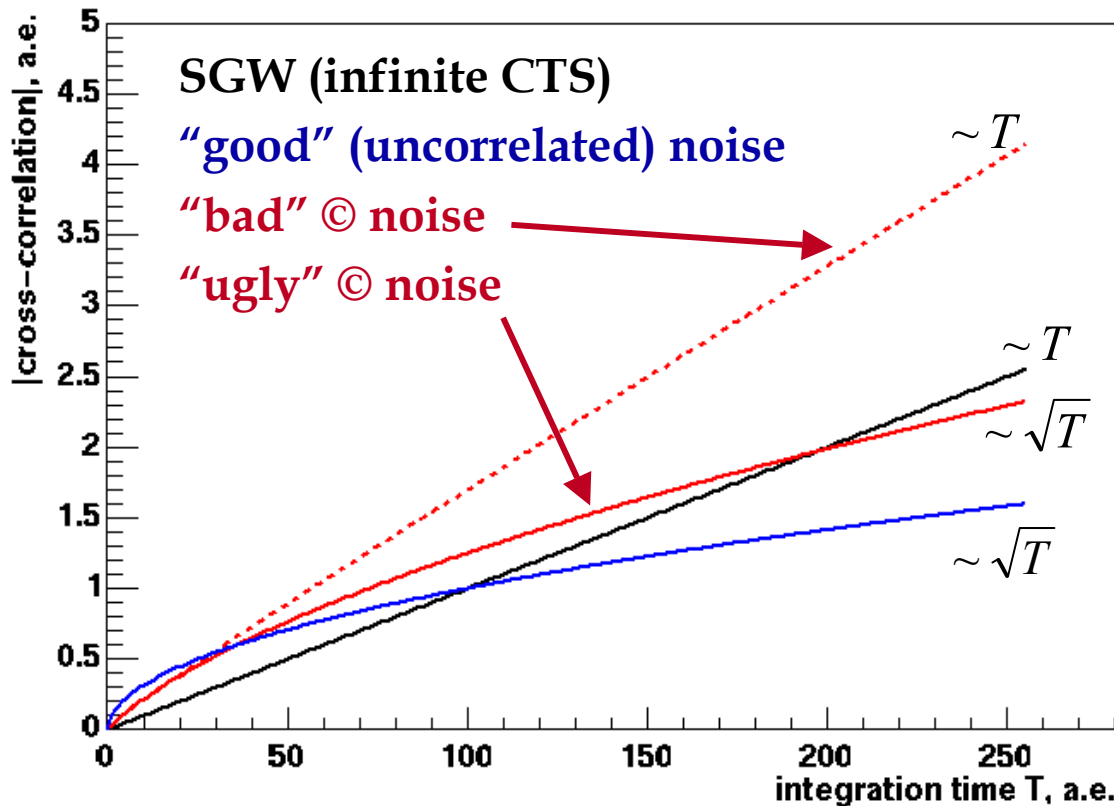
- **$A(f)$  is more robust than  $P(f)$  if noise is non-stationary**

- **test with simulated noise**

➤ Gaussian noise ( $\sigma_g$ ) + tail : total rms  $\sigma_n$

$\sigma_n / \sigma_g$	P	A
1.0	0.45	0.0266
1.45	0.94	0.0274
2.31	2.40	0.0273

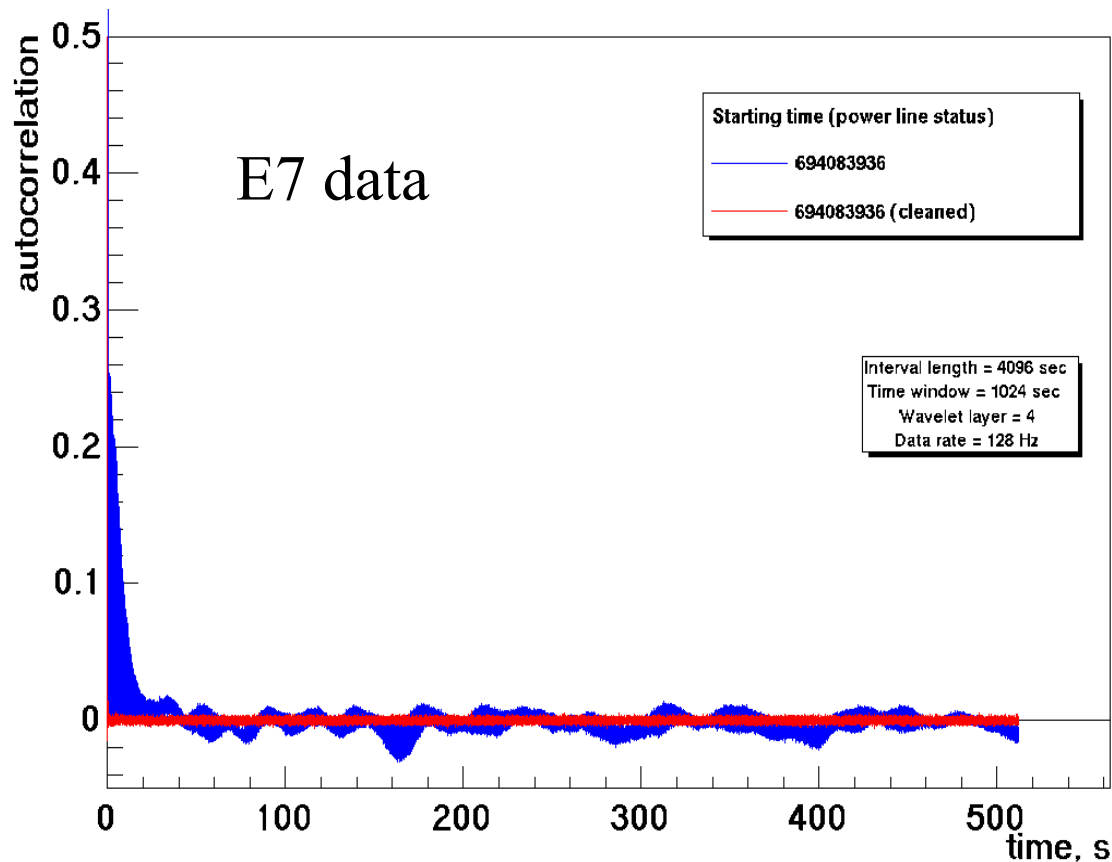
$$C = \langle h_L + n_L, h_H + n_H \rangle = \langle h_L, h_H \rangle + \langle n_L, n_H \rangle$$



- remove "bad" © noise (likely to be data processing artifacts)
- How to deal with "ugly" © noise?

- sign statistics  $s(t) = \{u_x u_y\}$
- $a(t)$  - autocorrelation function of  $s(t)$ 
  - a measure of correlated noise.

X-correlation of  
L1:AS\_Q & H2:AS\_Q  
in wavelet domain:  
32-64 Hz band



- uncorrelated noise

- autocorrelation function:  $a(0) = 1, a(\tau \geq \Delta t) = 0$

- null hypothesis: *data sets are not correlated*

- variance:  $\text{var}_0(\gamma) = \frac{1}{n}$

- correlated noise with time scale  $< T_s$

- autocorrelation function:  $a(\tau < T_s) = a_n(\tau), a(\tau > T_s) = 0$

- null hypothesis: *data sets are not correlated at time scale  $> T_s$*

- variance:  $\text{var}_{T_s}(\gamma) = \frac{1}{n} R,$

$$R = 1 + \sum_{m=1}^{T_s / \Delta t} (n - m) a_n(m \Delta t)$$

- **SCT allows calculate  $\text{var}(\gamma)$ , depending on the noise model.**

- **variance ratio**

$$R = \frac{\text{var}_{T_s}(\gamma)}{\text{var}_0(\gamma)}$$

- R is a measure of © noise, or quality of data.
- R times more data needed to reach same CL as for uncorrelated noise.
- If R is too large, the noise should be removed, if possible

- **residual correlated noise is handled by**

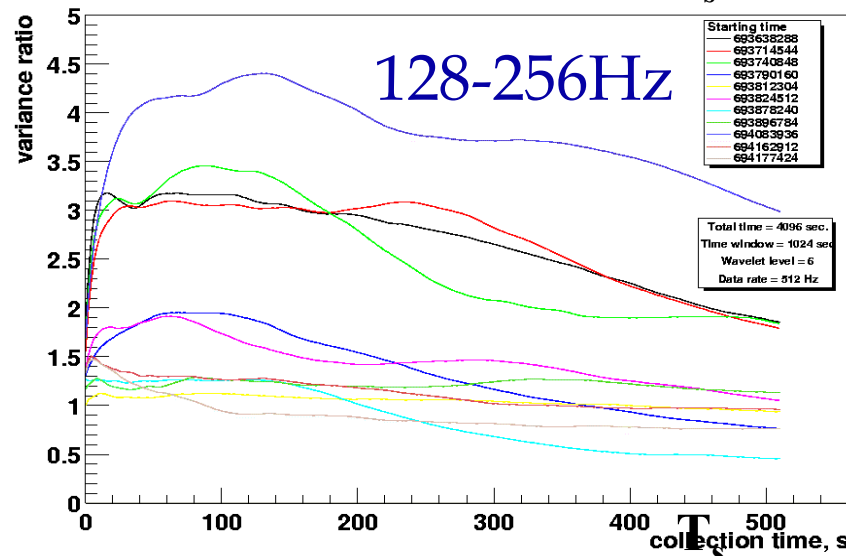
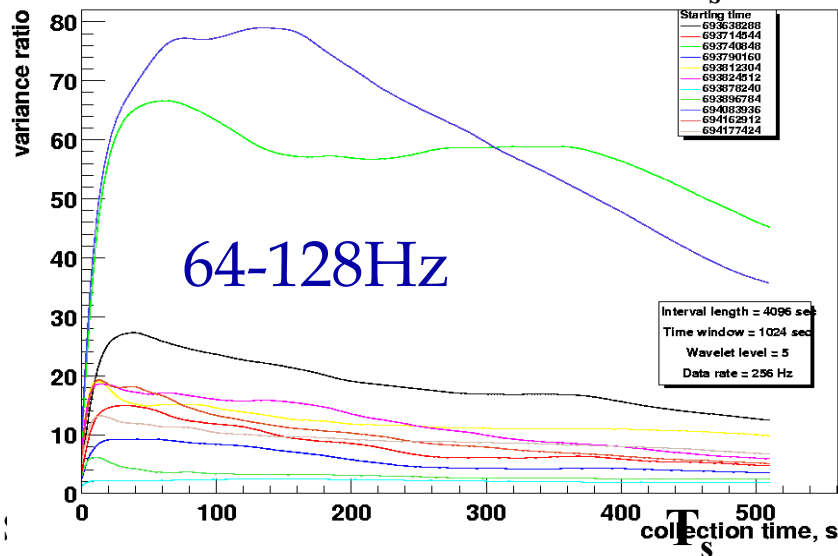
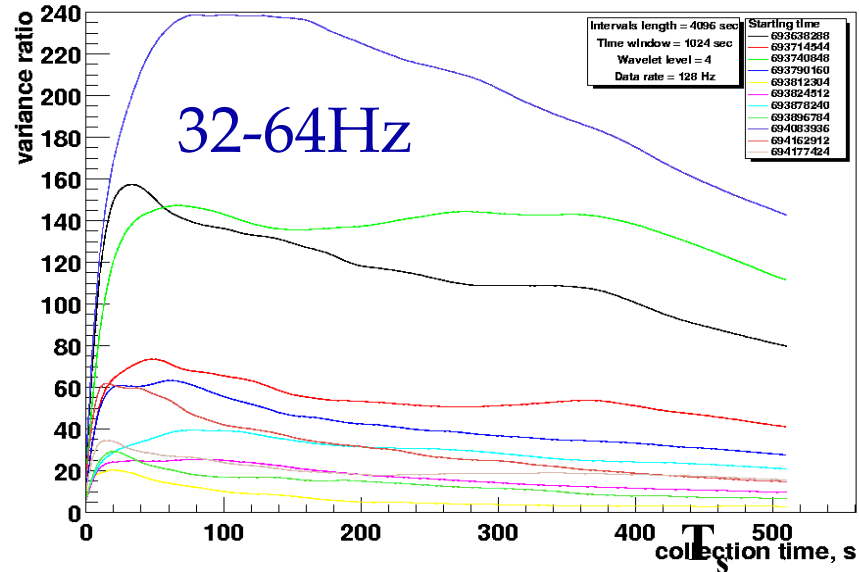
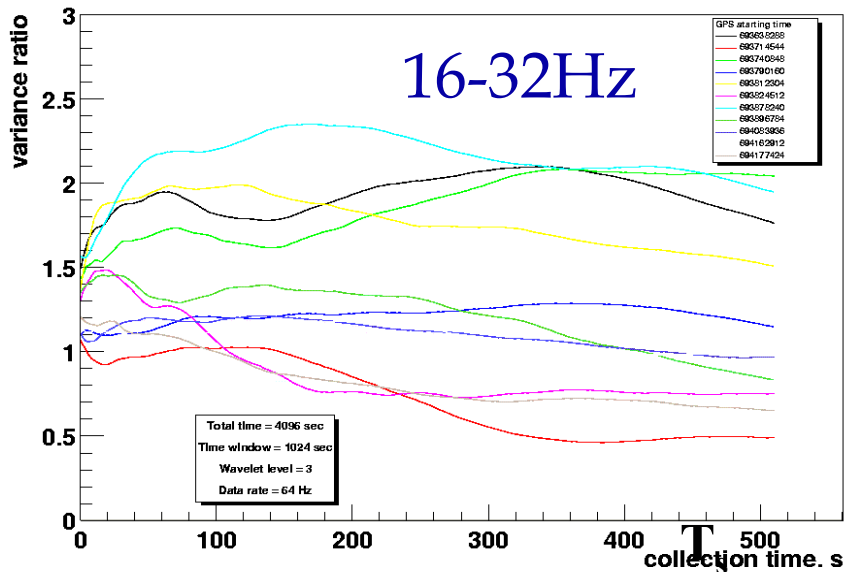
- reduced correlation coefficient:  $\gamma' = \gamma R^{-1}$

✓ normally distributed with variance  $1/n$

- **x-correlation in wavelet domain:**

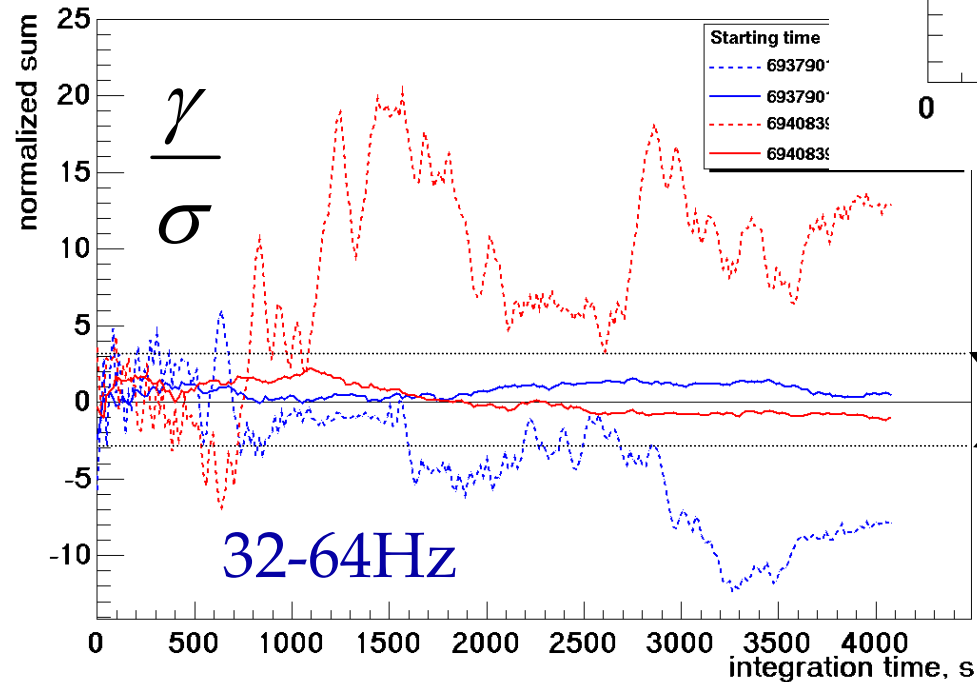
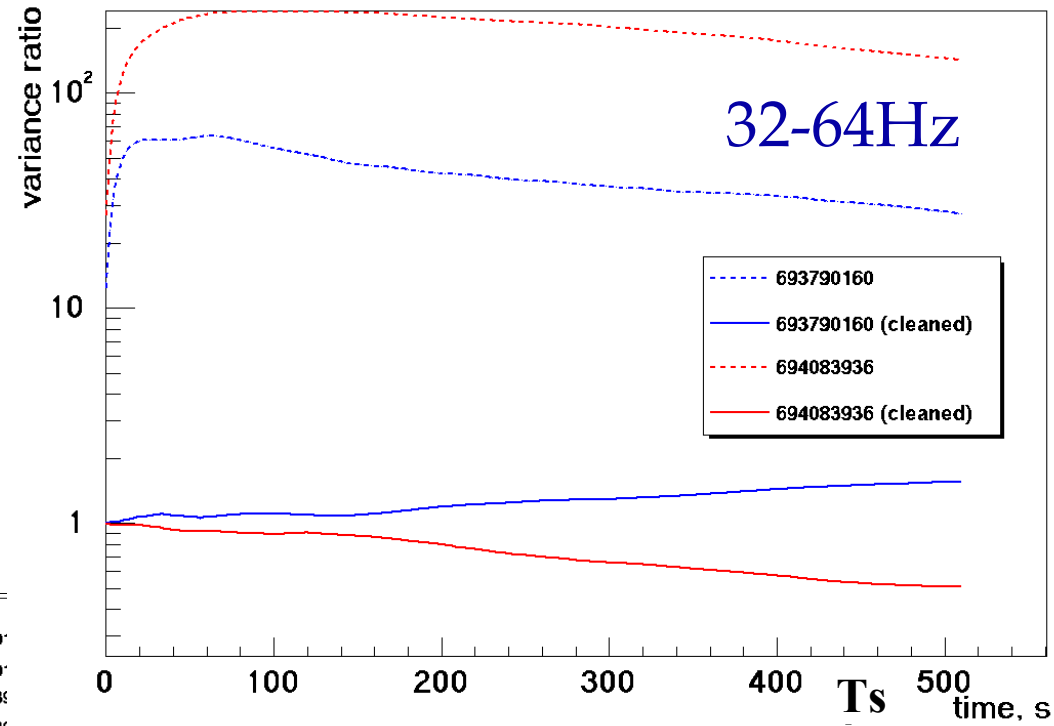
$$S_s = \sum_{n,\tau} \tilde{w}_n(\tau) \gamma'_n(\tau),$$

- L1xH2: 11 data segments 4096 sec each (total 12.5 h of E7 data)



- QMLR method was used

$\sigma$  - rms for uncorrelated noise



$\pm 3\sigma$

*dots - before*  
*solid - after*



1. *correlation coefficients*  $\gamma$  – measured
2. *variance of*  $\gamma$  – calculated for given model of © noise
  - © noise can be estimated from data if  $T_s \ll T$
3. *optimal coefficients*  $w$  – calculated for given SGW model.
  - **sign correlation efficiency**  $\varepsilon$  – estimated from simulation.
4. as a result of 1,2,3 calculate x-correlation  $S_s = \sum_{n,\tau} \tilde{w}_n(\tau) \gamma'_n(\tau)$ ,
5. find from simulation the dependence  $S(\Omega_{sim}) (\sim a\Omega_{sim})$
6. Set upper limit by calculating confidence belts.

- A robust correlation test with treatment of © noise is described. It allows:
  - **calculate x-correlation distribution if noise is not Gaussian**
  - **work with non-stationary noise**
  - **use a simple model of correlated noise**
- suggested method offers a good tool to estimate contribution from © noise.
  - **On E7 data it is shown how © noise affects the x-correlation.**
- we suggest to use sign x-correlation as a complementary method for setting SGW upper limit
  - **very simple and CPU efficient**

